



CEPC vertex Detector

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(On behalf of the CEPC physics and detector group)



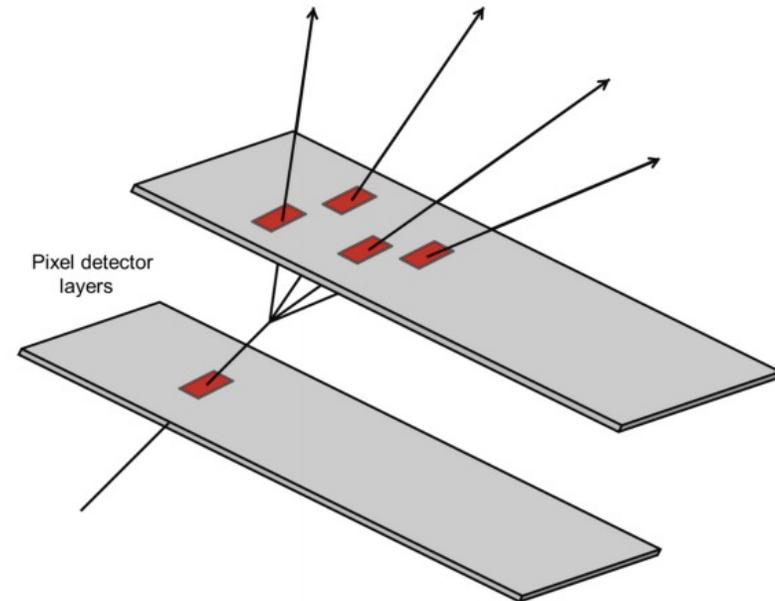
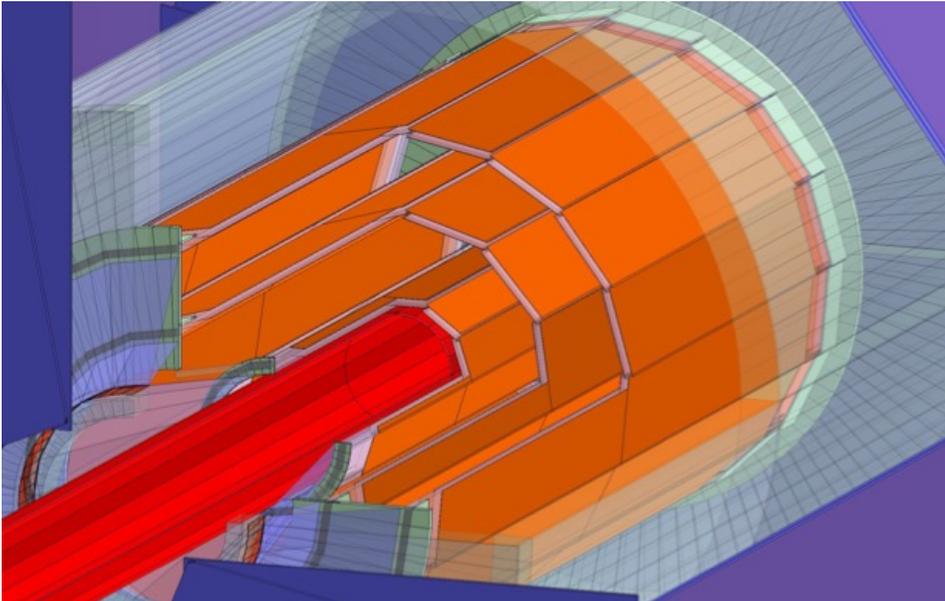
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Chinese Academy of Sciences

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Introduction: vertex detector

- Vertex detector optimized for first 10 year of operation
 - Higgs factory , low luminosity Z factory
- Motivation:
 - Aim to optimize impact parameter resolution and vertexing capability
 - Key detector for $H \rightarrow cc$ and $H \rightarrow gg$ physics, which is an important goal for CEPC

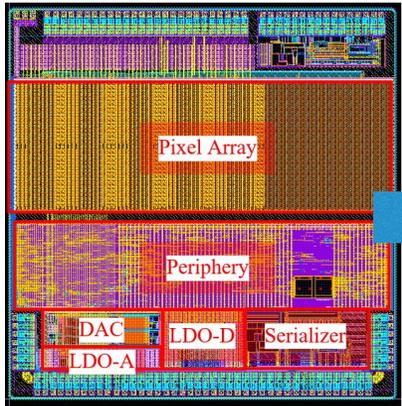


Vertex Requirement

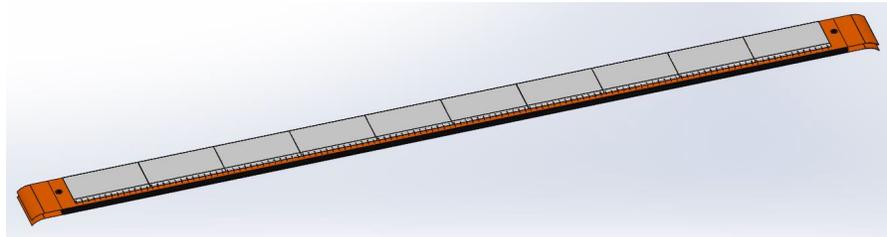
- Inner most layer (b-layer) need to be positioned as close to beam pipe as possible
 - **Challenges:** b-layer radius (11mm) is smaller compared with ALICE ITS3 (18mm)
- High data rate: (especially at Z pole , ~43MHz, 1Gbps per chip)
 - **Challenges:** 1Gbps per chip high data rate especially at Z pole
- Low material budget (less than 0.15%X0 per layer)
- Detector Cooling with air cooling (power consumption \leq 40 mW/cm²)
- Spatial Resolution (3-5 um)
- Radiation level (~1Mrad per year in average)

CEPC vertex detector prototype R & D

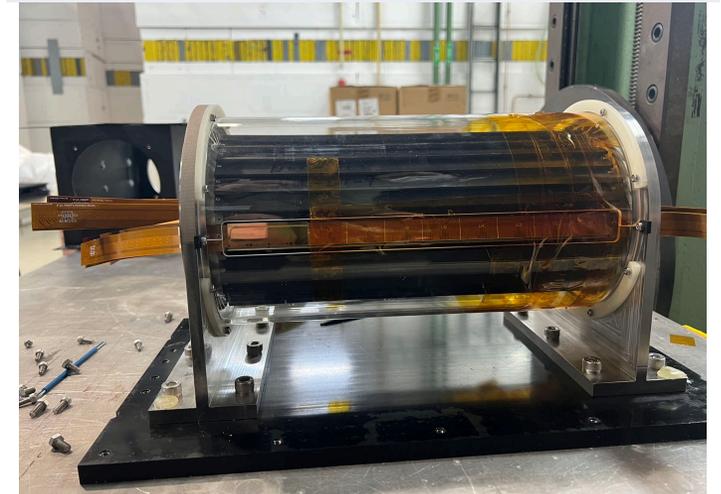
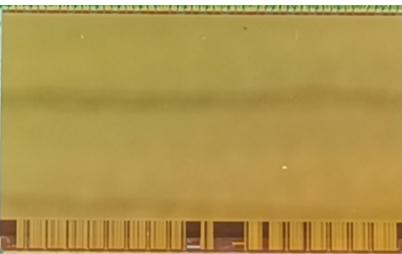
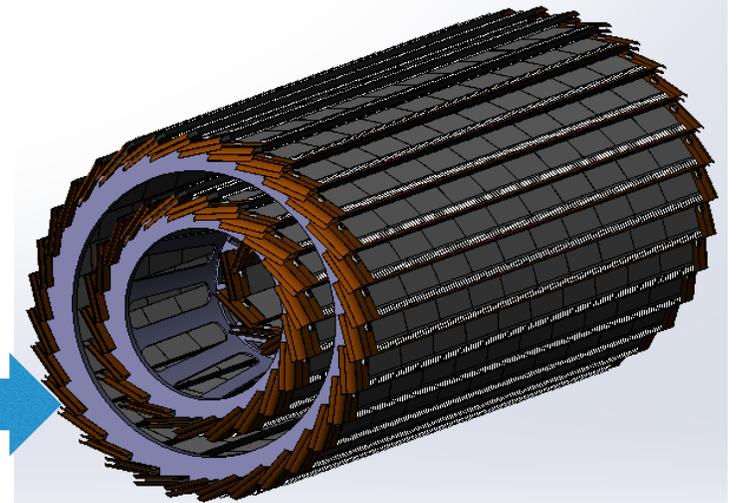
CMOS Sensor chip development



Detector module (Ladder) Prototyping

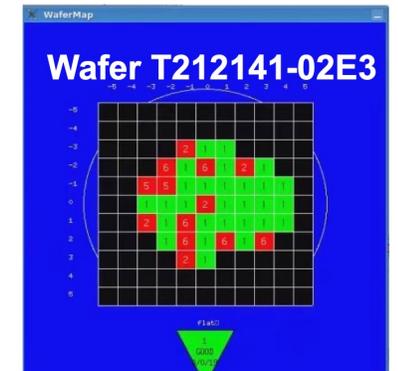
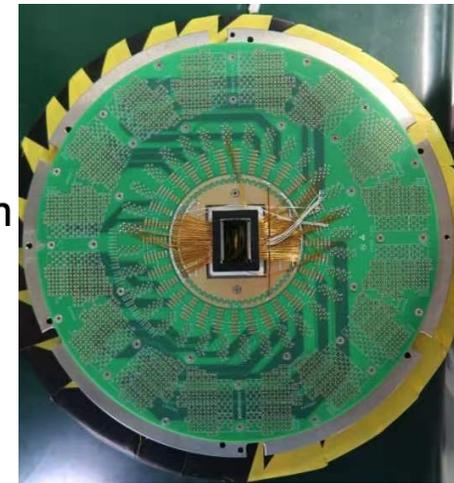
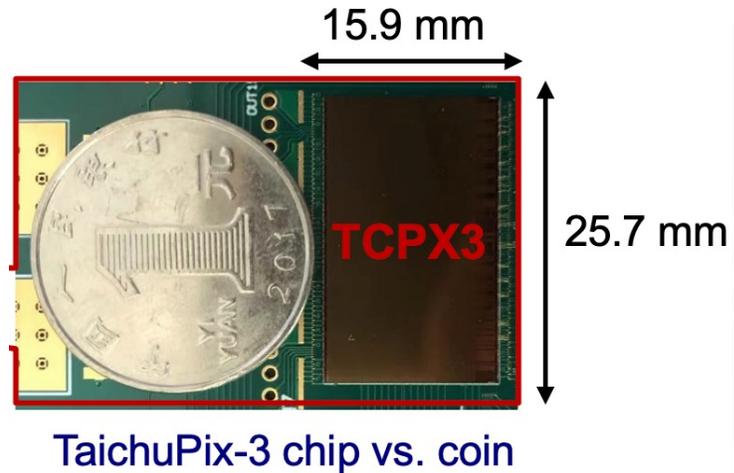
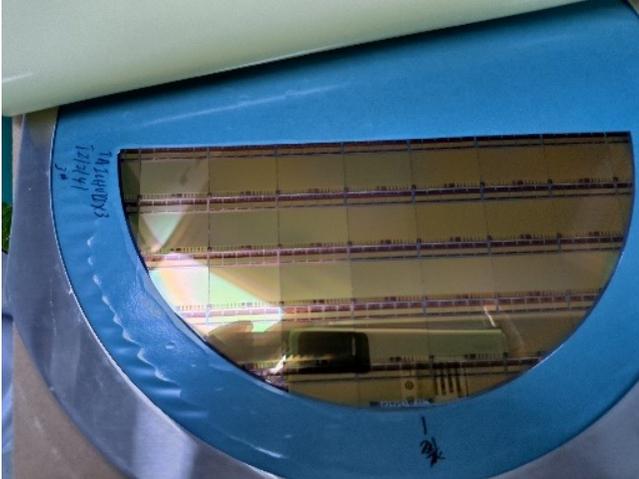


Vertex detector prototype



R&D efforts: Full-size TaichuPix3

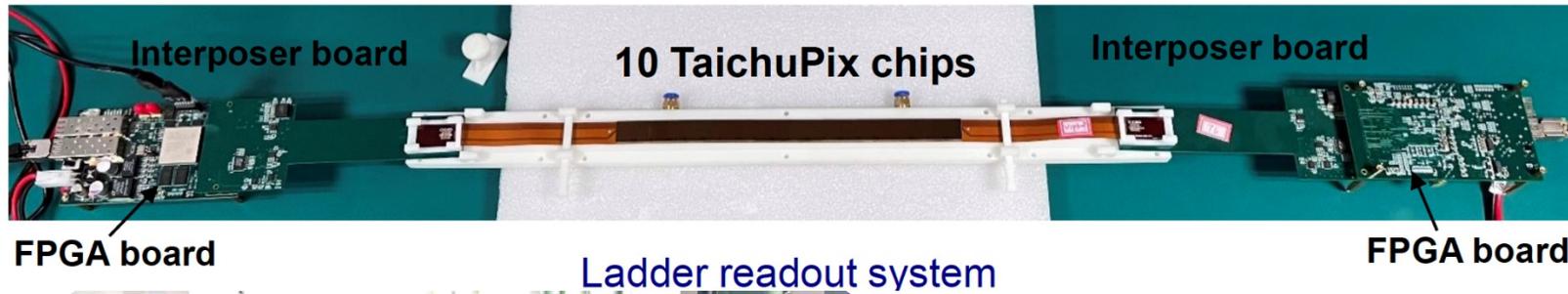
- Full size CMOS chip developed, 1st engineering run
 - 1024×512 Pixel array, Chip Size: 15.9×25.7mm
 - 25μm×25μm pixel size with high spatial resolution
 - Process: Towerjazz 180nm CIS process
 - Fast digital readout to cope with ZH and Z runs (support 40MHz clock)



An example of wafer test result

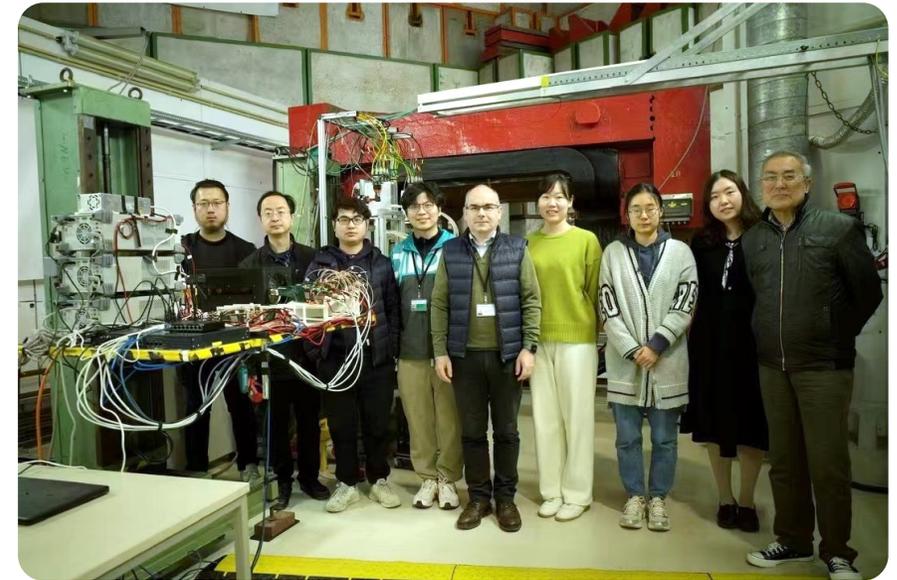
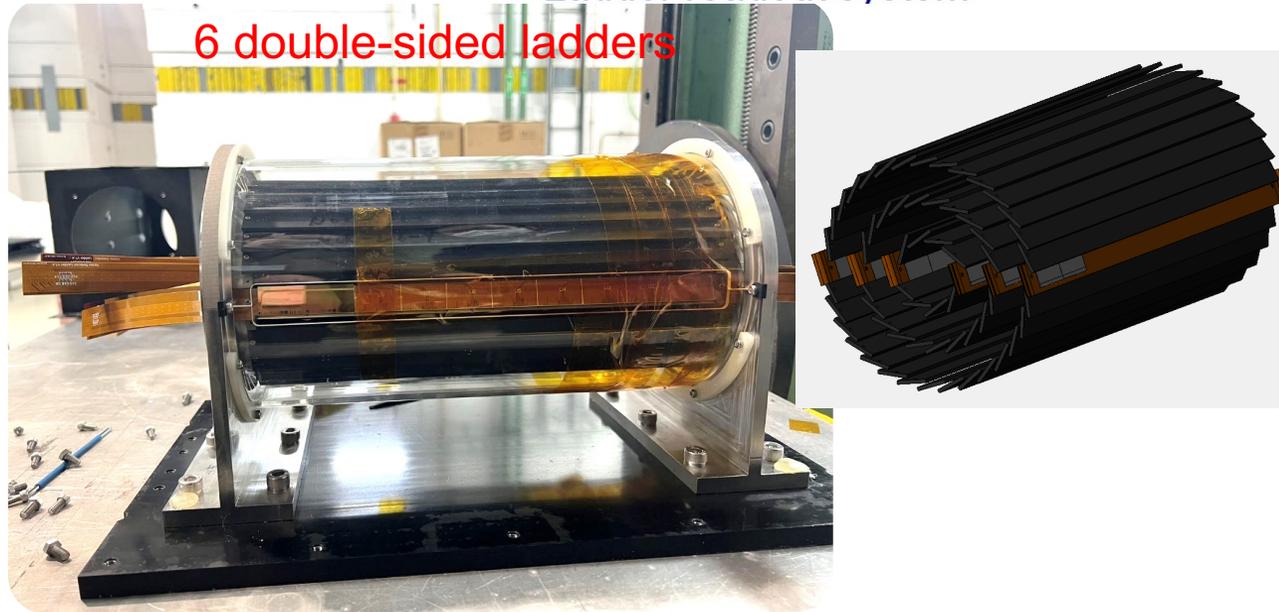
	Status	CEPC Final goal
CMOS chip technology	Full-size chip with TJ 180nm CIS	65nm CIS

R&D effort: vertex detector prototype



TaichuPix-based prototype detector tested at DESY in April 2023

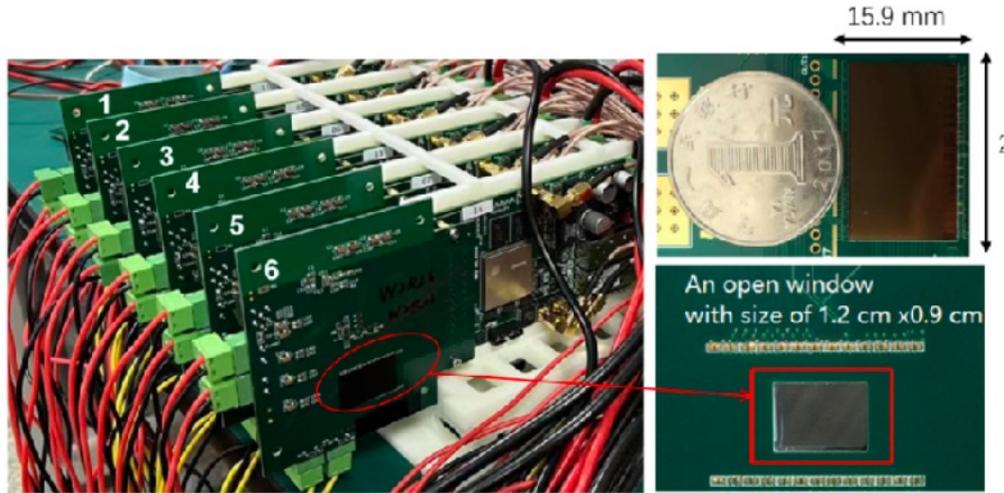
Spatial resolution $\sim 4.9 \mu\text{m}$



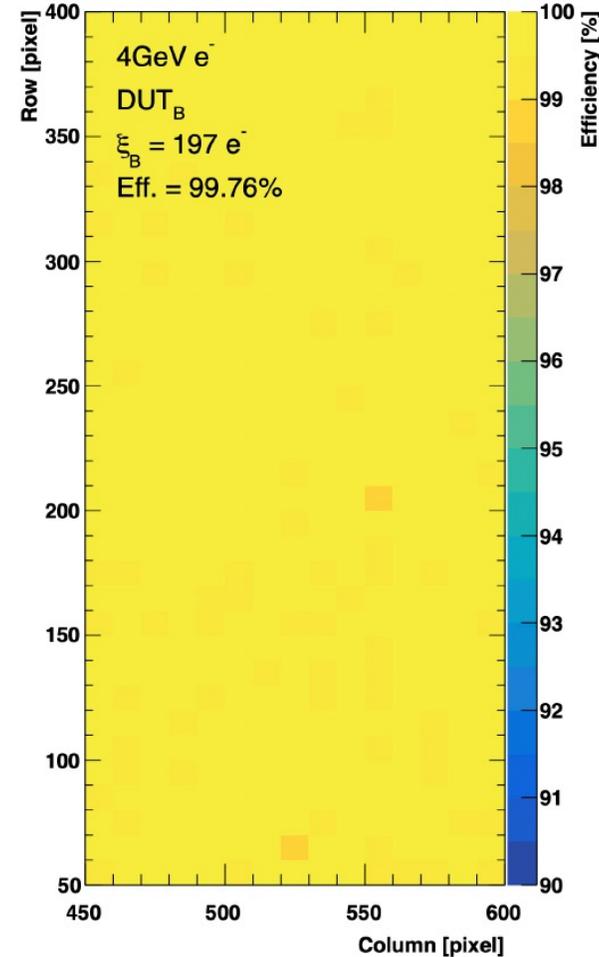
	Status	CEPC Final goal
Detector integration	Detector prototype with ladder design	Detector with bent silicon design

R&D efforts and results: Jadepix3/TaichuPix3 beam test @ DESY

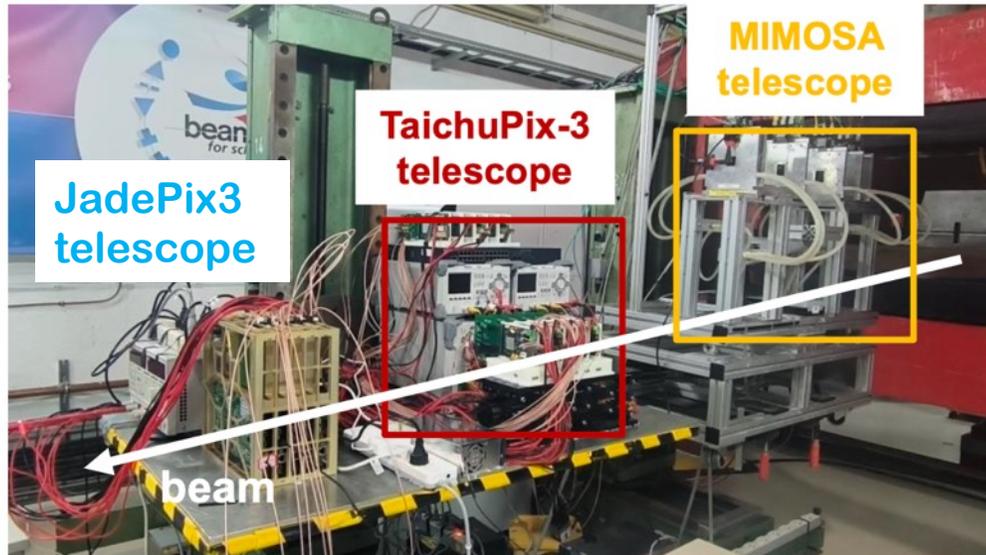
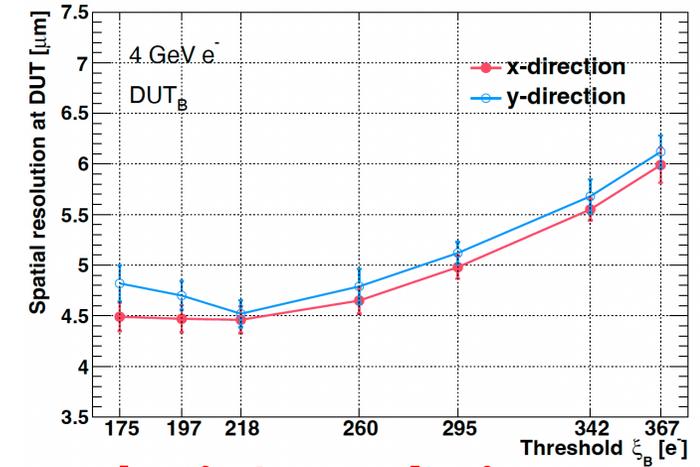
Spatial resolution 4~5um, Efficiency >99%



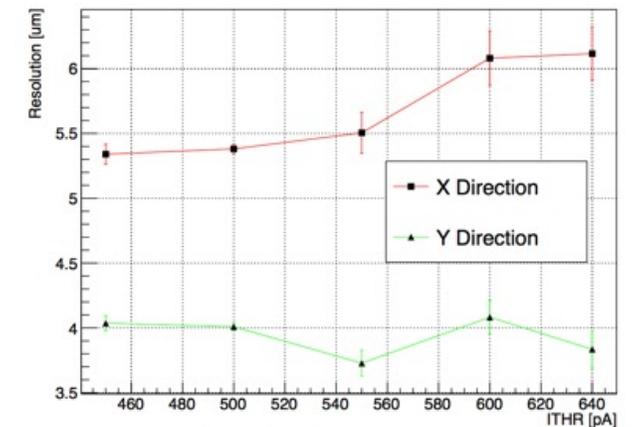
TaichuPix3 efficiency



TaichuPix3 resolution



JadePix3 resolution



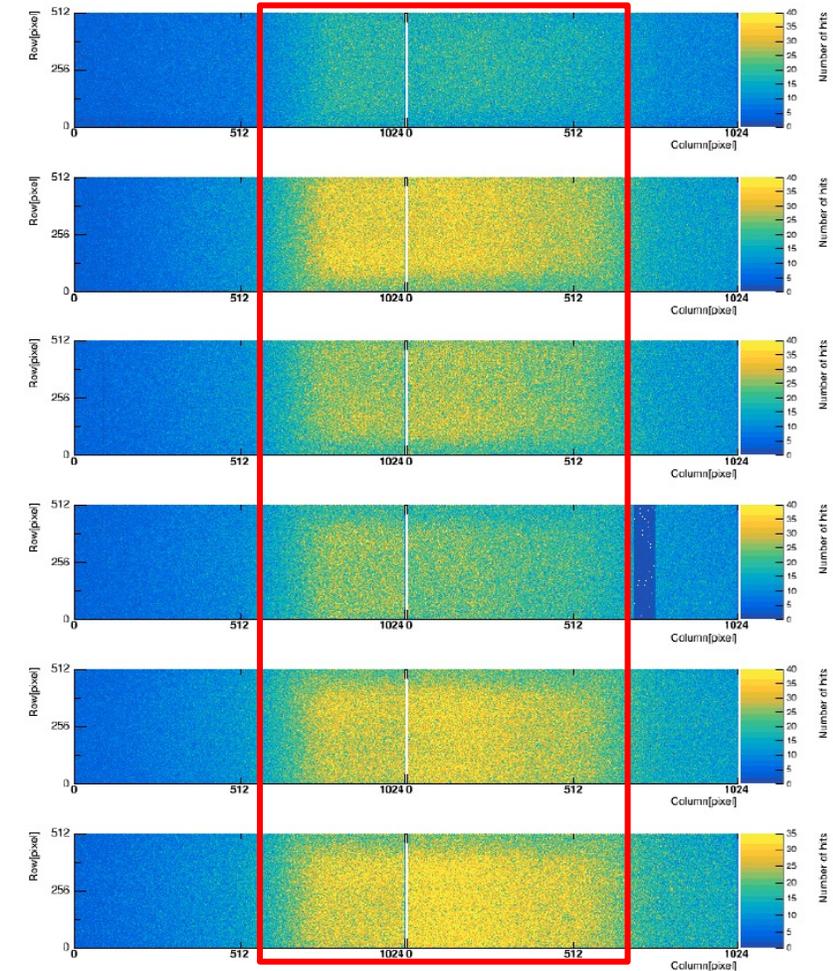
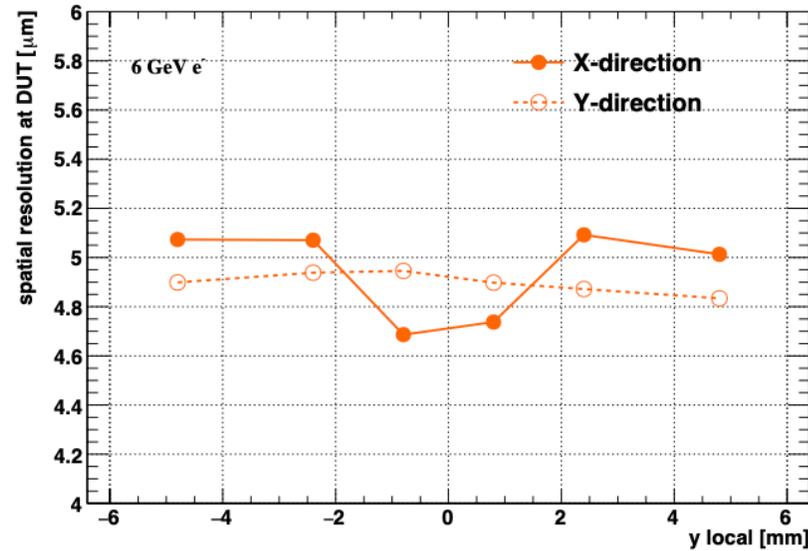
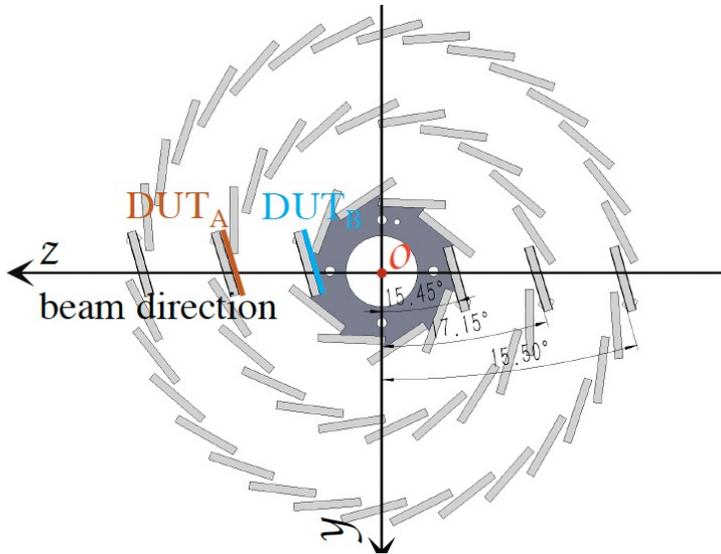
Collaboration with CNRS and IFAE in Jadepix/TaichuPix R & D

R&D efforts and results: vertex detector prototype beam test

Spatial resolution $\sim 5 \mu\text{m}$

Hit maps of multiple layers of vertex detector

Beam spot



	Status	CEPC Final goal
Spatial resolution	4.9 μm	3-5 μm

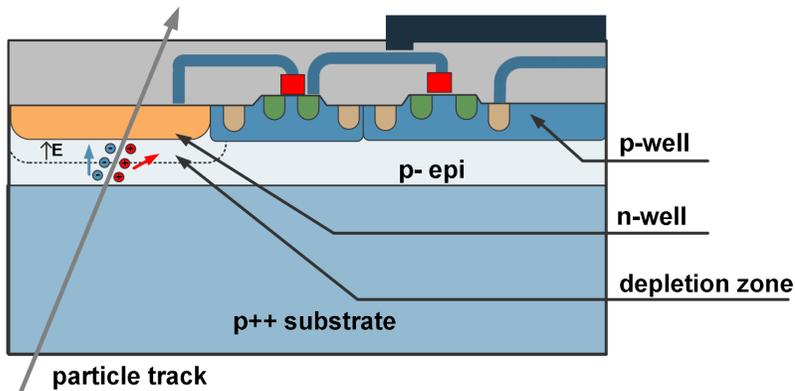
Technology survey and our choices

■ Vertex detector Technology selection

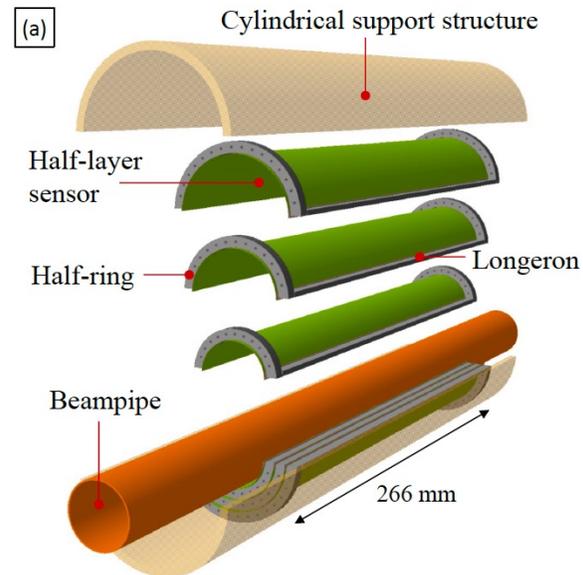
- Baseline: based on curved CMOS MAPS (Inspired by ALICE ITS3 design[1])
 - Advantage: 2~3 times smaller material budget compared to alternative (ladder)
- Alternative: Ladder design based on CMOS MAPS

Monolithic active Pixel CMOS (MAPS)

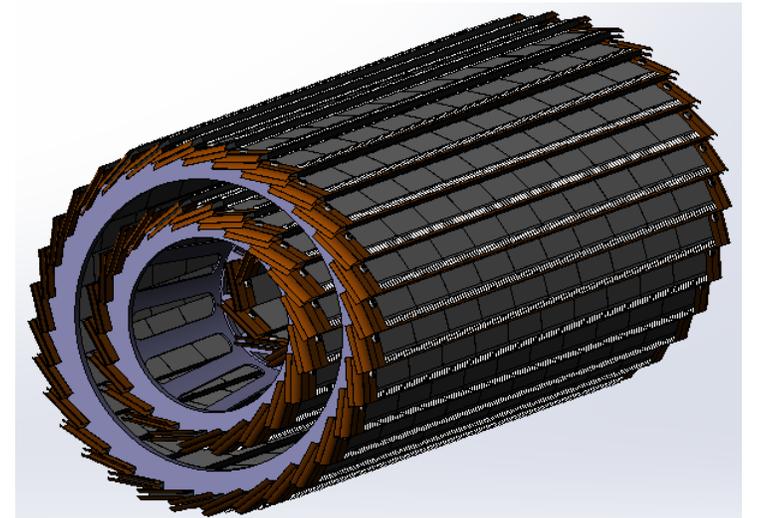
Monolithic Pixels



Baseline: curved MAPS



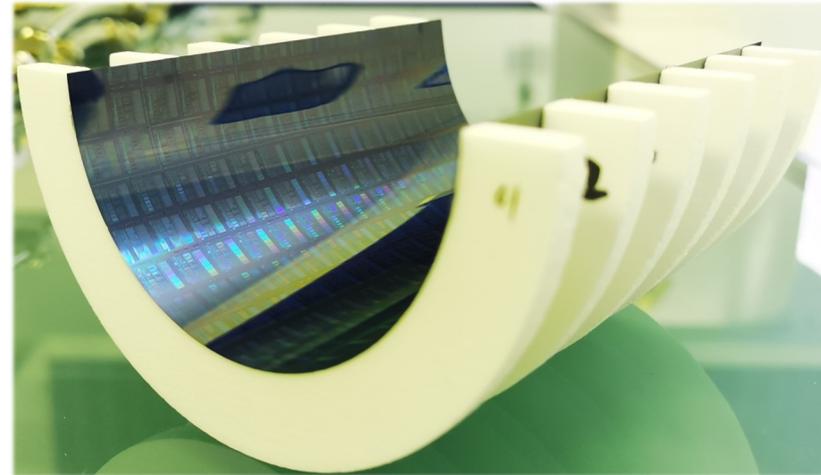
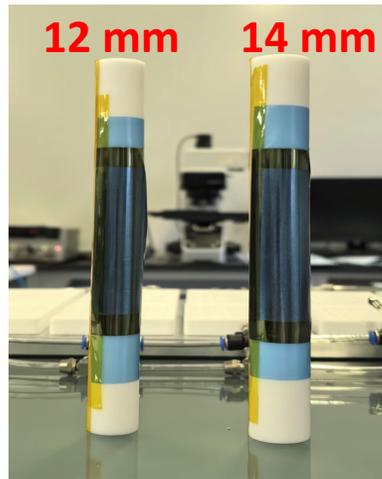
Alternative: ladder based MAPS



[1] ALICE ITS3 TDR: <https://cds.cern.ch/record/2890181>

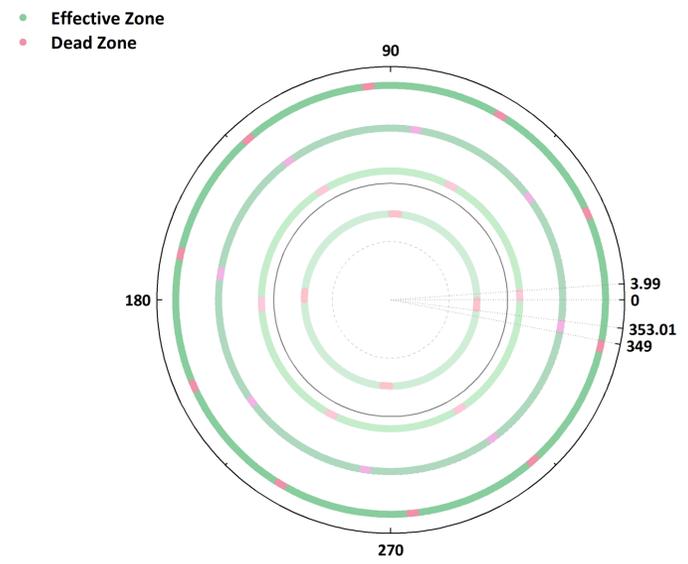
R&D efforts curved MAPS

- CEPC b-layer radius (11mm) smaller compared with ALICE ITS3 (radius=18mm)
- Feasibility : Mechanical prototype with dummy wafer can curved to a radius of 12mm
 - The dummy wafer has been thinned to 40 μ m



	Status	CEPC Final goal
Bent silicon with radius	Bent Dummy wafer radius ~12mm	Bent final wafer with radius ~11mm

Baseline: bent MAPS

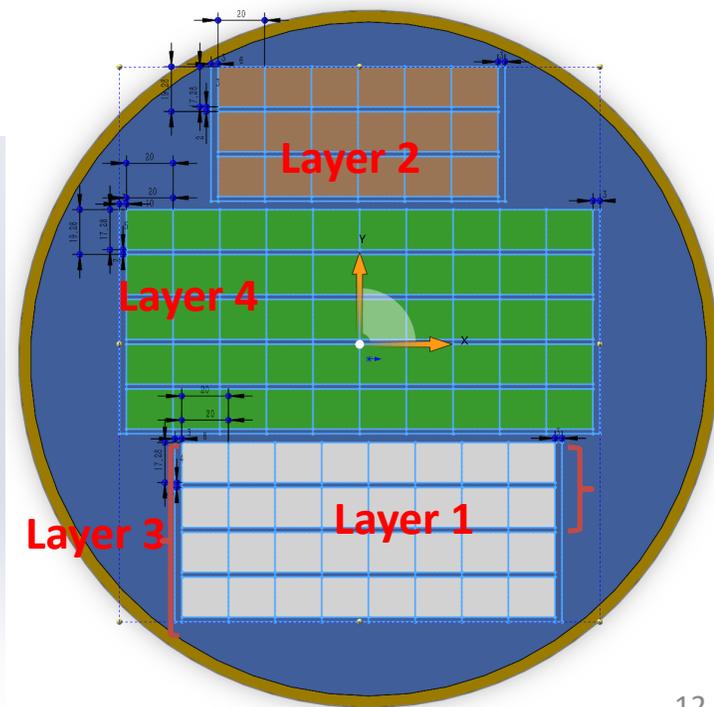
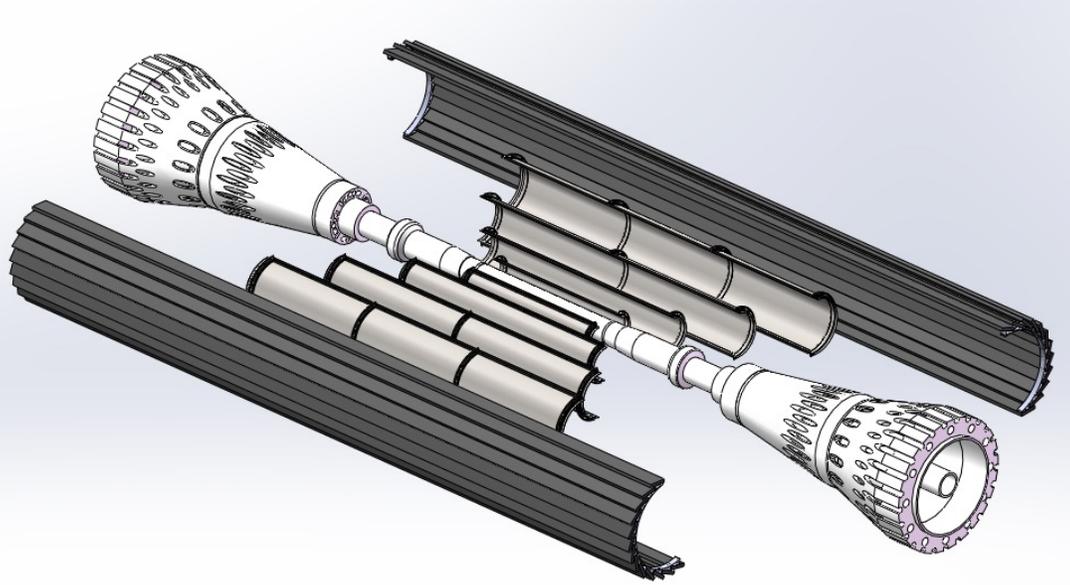


Schematic diagram of the Inner layer placement of the vertex detector stitching scheme.

- 4 single layer of bent MAPS + 1 double layer ladder
 - Material budget is much lower than alternative option
- Use single bent MAPS for Inner layer ($\sim 0.15\text{m}^2$)
 - Low material budget $0.06\%X_0$ per layer
 - Different rotation angle in each layer to reduce dead area

Long barrel layout (no endcap disk)
to cover $\cos \theta \leq 0.991$

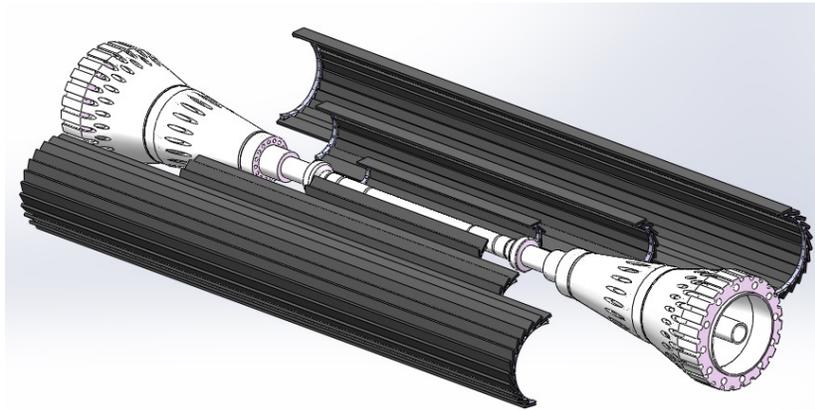
layer	Radius	Material
Layer 1	11mm	0.06% X_0
Layer 2	16.5mm	0.06% X_0
Layer 3	22mm	0.06% X_0
Layer 4	27.5mm	0.06% X_0
Layer 5/6 (Ladders)	35-40 mm	0.33% X_0
Total		0.57% X_0



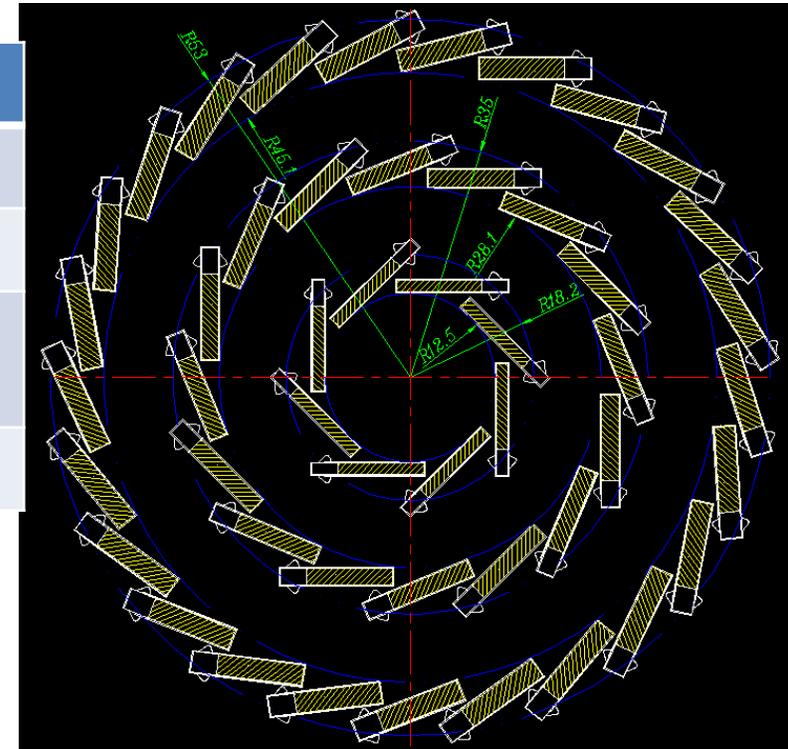
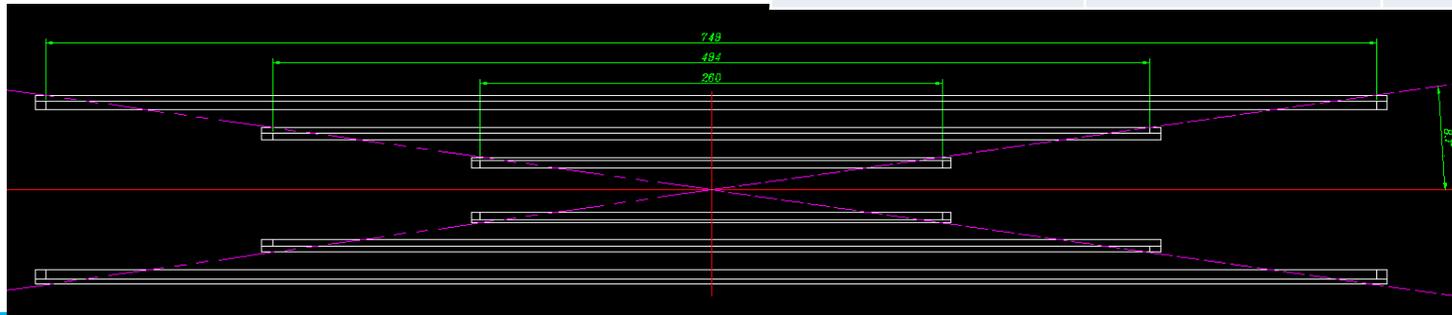
Alternative : CMOS ladder

Alternative: CMOS chips with a long ladder layout

- 3 double-side layer with long ladders design
- We have built a vertex prototype based on the short ladders design
- No effective solution for inner layer cooling yet.



layer	Radius	Material
Layer 1/2	12.5 -18 mm	~0.33% X0
Layer 3/4	28 - 35mm	~0.33% X0
Layer 5/6 (Ladders)	45 - 53mm	~0.33% X0
Total		~1% X0



Data rate estimation of vertex detector

	Hit rate (MHz/cm ²)	Data rate@triggerless (Gbps/cm ²)
Higgs	0.61	0.18
WW	3.16	0.98
Low lumi Z pole	3.9	1.2

- Data rate is dominated by background from pair production
- WW runs and low Lumi Z runs (20% of high lumi Z)
- Data rate @1.2Gbps per chip for triggerless readout

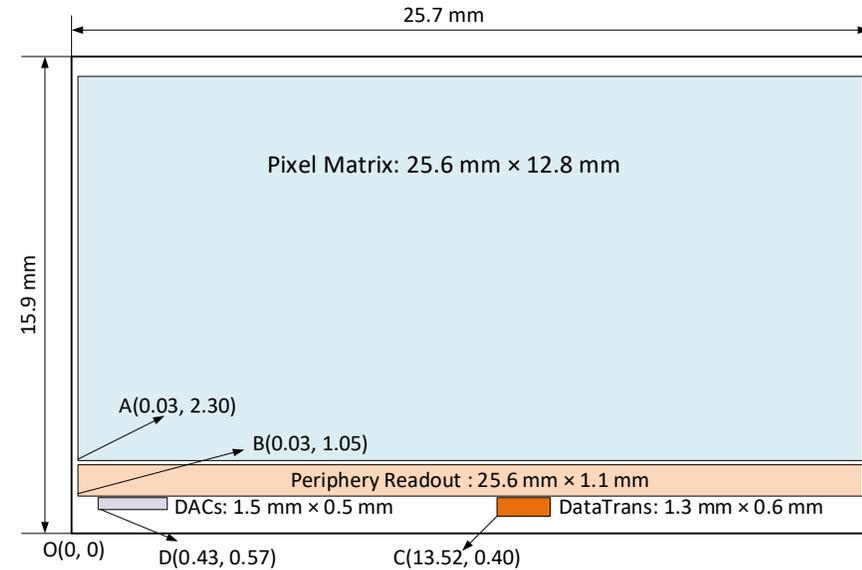
Chip design for ref- TDR and power consumption

Power consumption

- Fast priority digital readout for 40MHz at Z pole
- 65/55nm CIS technology
- Power consumption can be reduced to $\sim 40\text{mW}/\text{cm}^2$

Air cooling feasibility study

- Baseline layout can be cooled down to $\sim 20^\circ\text{C}$
 - Based on 3 m/s air speed, estimated by thermal simulation



	Matrix	Periphery	DataTrans.	DACs	Total Power	Power density
65nm for TDR @ 1 Gbps/chip (TDR LowLumi Z)	60 mW	80 mW	36 mW	10 mW	186 mW	$\sim 40\text{ mW}/\text{cm}^2$

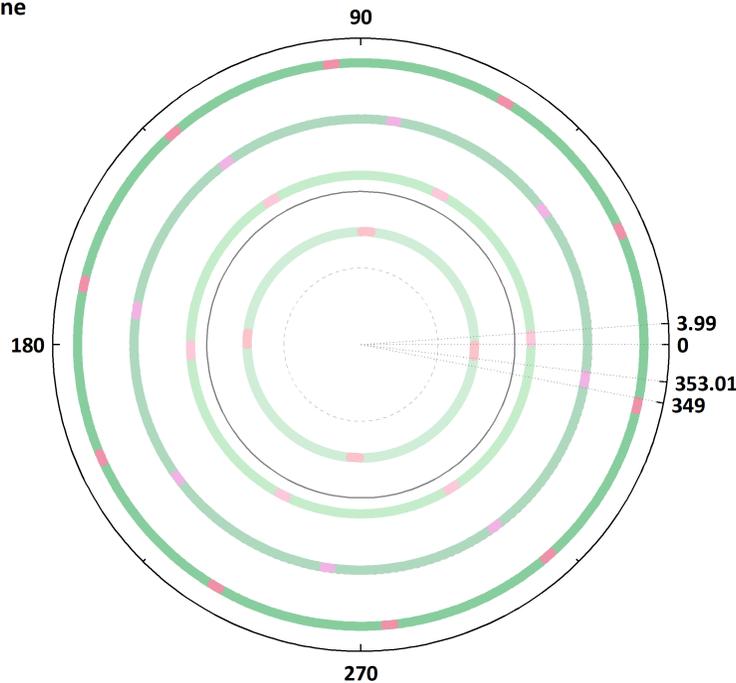
Performance: impact parameter resolution

Compared to alternative (ladder) option

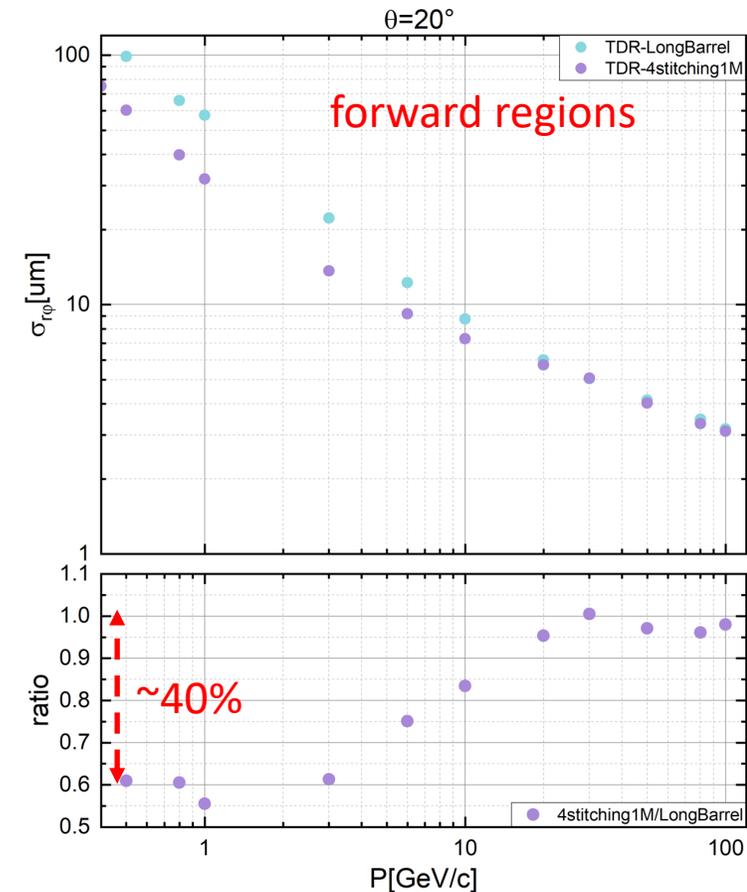
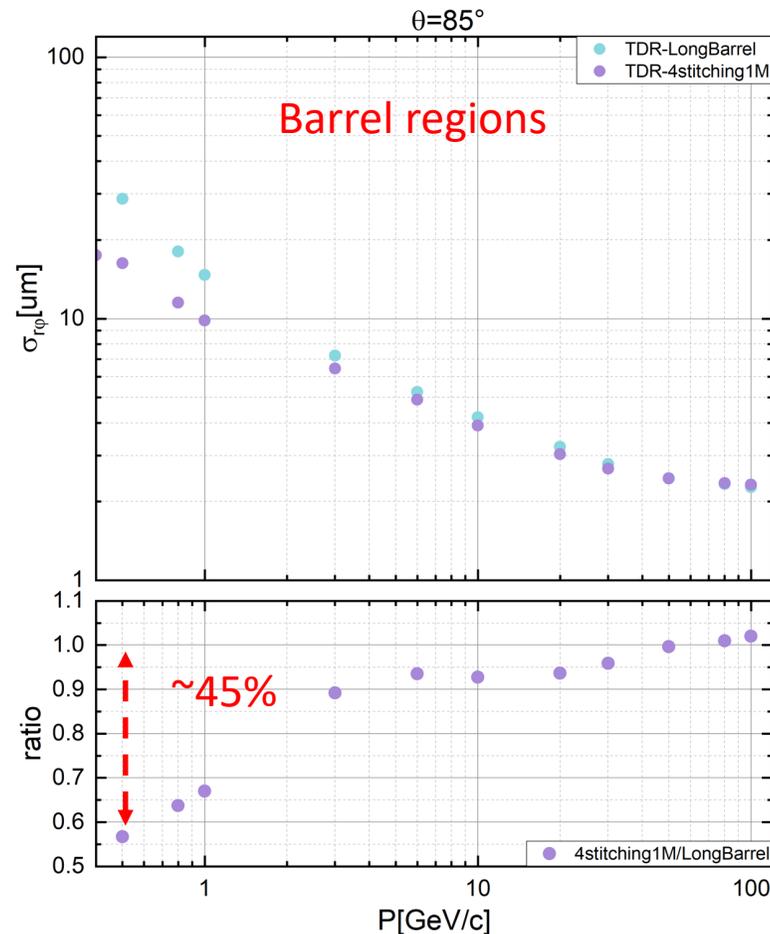
– baseline (stitching) has significant improvement ($\sim 45\%$) in low momentum case

Different rotation angle in each layer to reduce dead area

- Effective Zone
- Dead Zone



Schematic diagram of the Inner layer placement of the vertex detector stitching scheme.



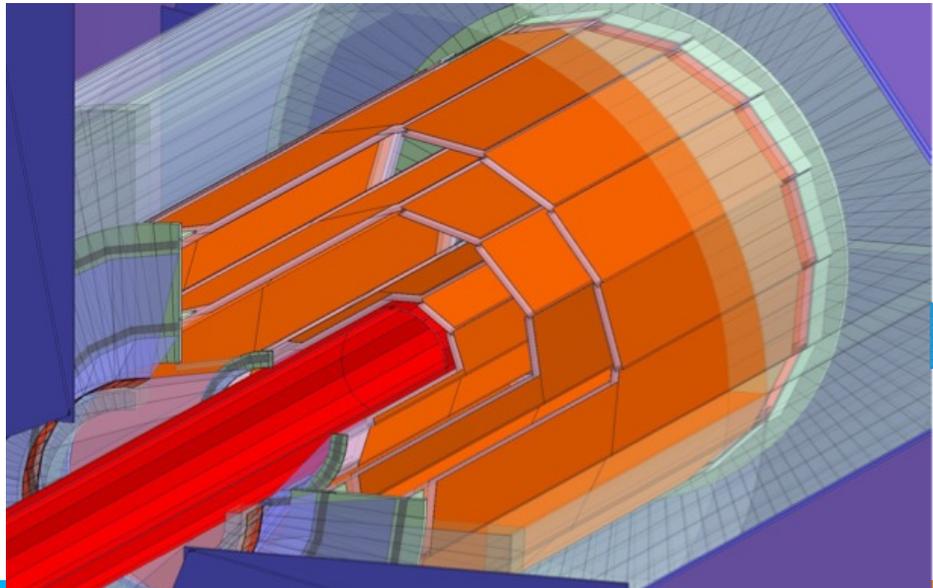
Contributions and Collaborations

- IHEP Beijing: Chip designs, electronics, DAQ and prototype assembly
- IPHC/CNRS: Collaboration in framework of FCPPL, BELLE II upgrade
- IFAE: Collaboration in Taichu chip design
- ShanDong U.: Stitching chip design, Taichu chip design
- CCNU: Jadxix chip design
- Northwestern Polytechnical U. : Taichu Chip design
- Nanchang U. : Taichu chip design
- Nanjing U. : testbeam study

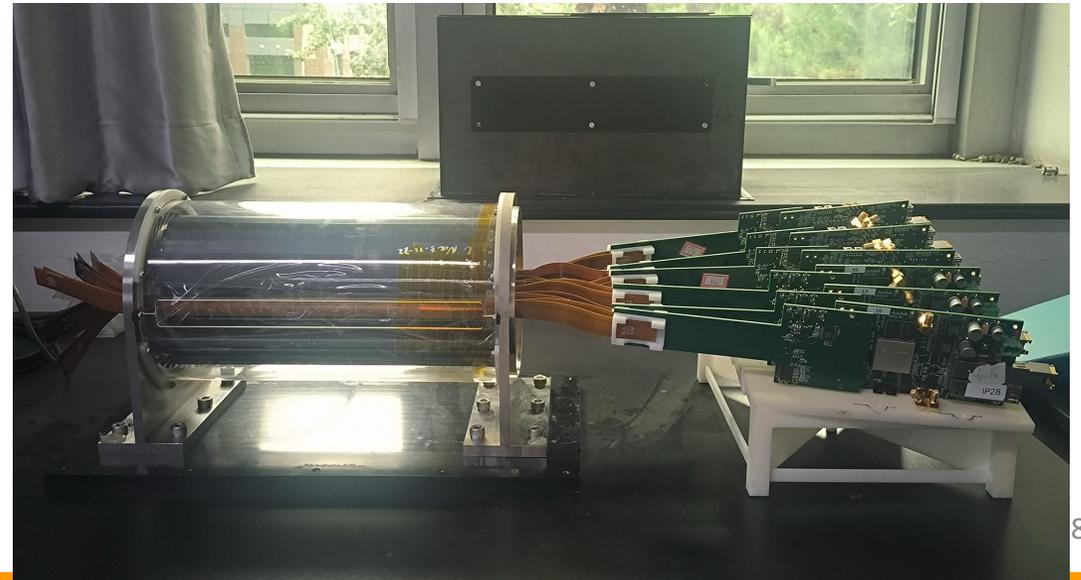
Summary

- 1st full-size Prototype based the ladder design for CEPC vertex detector has been developed
- The Curved MAPS option has been chosen as baseline for the reference detector TDR.
 - More R & D needed for this option
 - Preparing a work package proposal towards research for vertex detector in future lepton collider
 - Exploring synergies with other projects

CEPC vertex conceptual design (2016)



CEPC vertex prototype (2023)



Preliminary idea about working package

- Aim to develop vertex detector for future lepton collider
 - 3-5um spatial resolution
 - 40-43.3MHz clock, Can handle 1Gbps data rate in single chip level
 - Power consumption $\sim 40\text{mW}/\text{cm}^2$
 - Stitching design, can be used in for curved MAPS vertex detector

	Deliverables	Goal
2025	TJ180nm CIS stitching engineering run	Verify the stitching technology for high data rate
2026	TJ65nm CIS MPW chip (joint MPW runs ?)	Validate the basic design for 65nm technology
2027-2028	TJ65nm CIS engineering run	Validate final design



**Thank you for your
attention!**

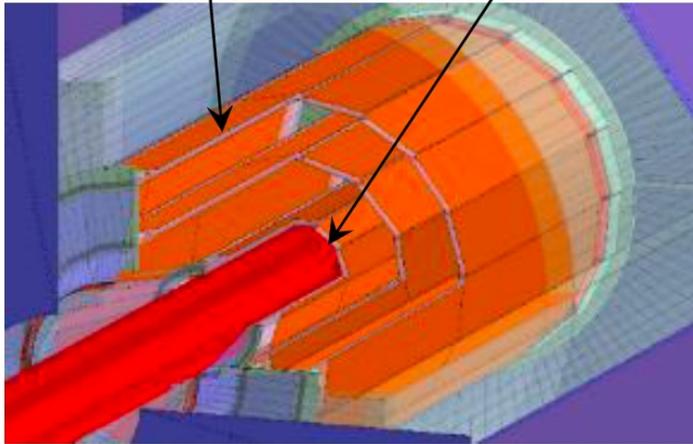


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Backup

Silicon Pixel Chips for Vertex Detector

2 layers / ladder $R_{in} \sim 16$ mm



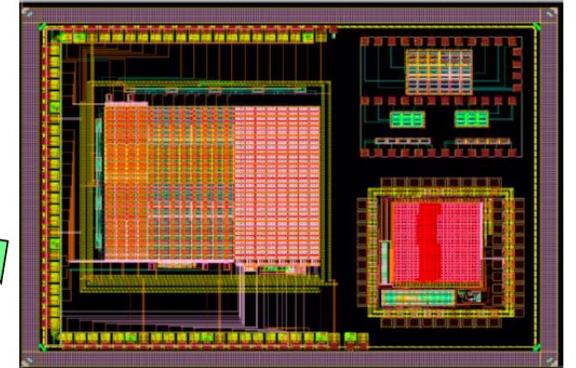
Goal: $\sigma(IP) \sim 5 \mu\text{m}$ for high P track

CDR design specifications

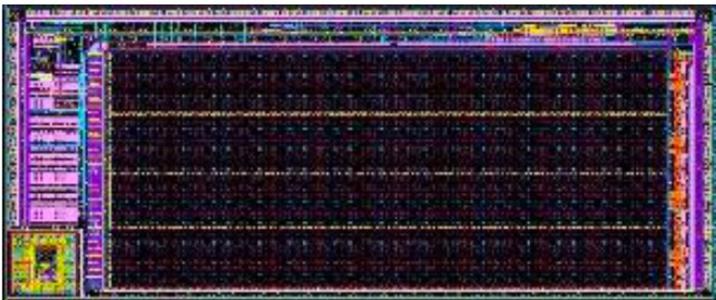
- Single point resolution $\sim 3 \mu\text{m}$
- Low material ($0.15\% X_0$ / layer)
- Low power ($< 50 \text{ mW/cm}^2$)
- Radiation hard (1 Mrad/year)

Silicon pixel sensor develops in 5 series:
JadePix, TaichuPix, CPV, Arcadia, COFFEE

Develop **COFFEE** for a CEPC tracker using SMIC 55nm HV-CMOS process



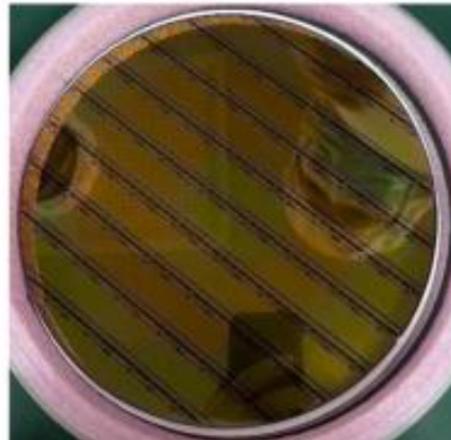
JadePix-3 Pixel size $\sim 16 \times 23 \mu\text{m}^2$



Tower-Jazz 180nm CiS process
Resolution 5 microns, 53 mW/cm^2

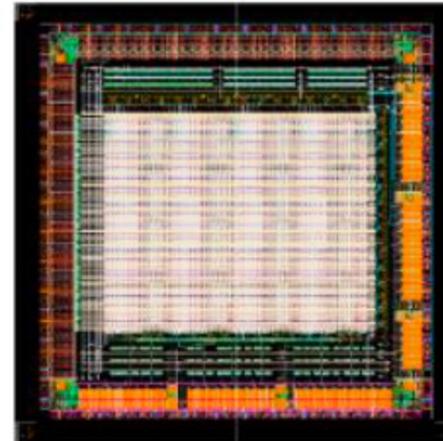
MOST 1

TaichuPix-3, FS $2.5 \times 1.5 \text{ cm}^2$
 $25 \times 25 \mu\text{m}^2$ pixel size



MOST 2

CPV4 (SOI-3D), 64×64 array
 $\sim 21 \times 17 \mu\text{m}^2$ pixel size

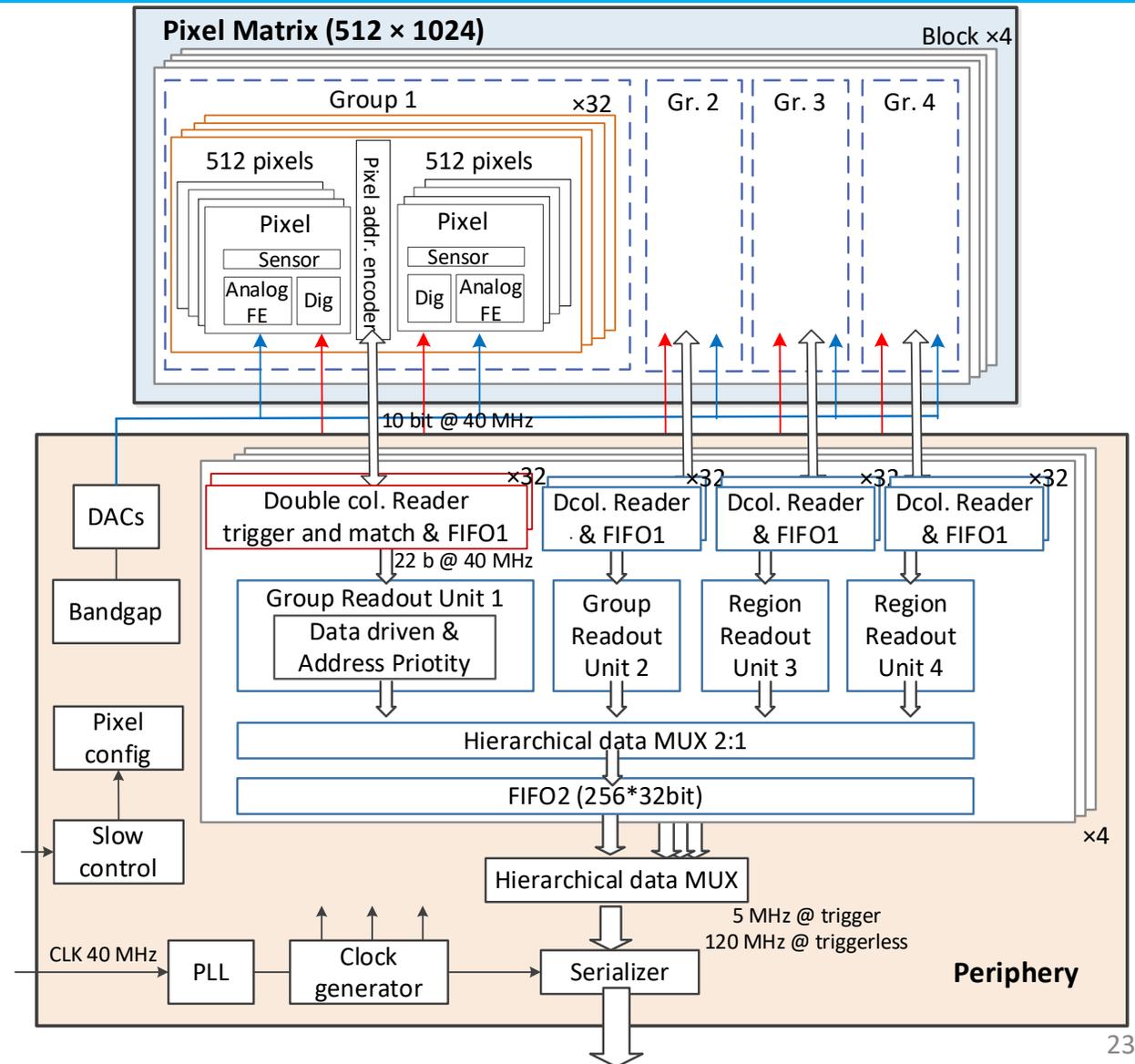


Arcadia by Italian groups
for IDEA vertex detector
LFoundry 110 nm CMOS



TaichuPix design

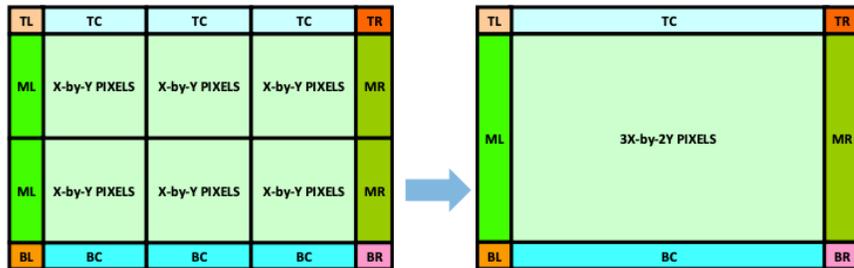
- Pixel 25 $\mu\text{m} \times 25 \mu\text{m}$
 - Continuously active front-end, in-pixel discrimination
 - Fast-readout digital, with masking & testing config. logic
- Column-drain readout for pixel matrix
 - Priority based data-driven readout
 - Readout time: 50-100 ns for each pixel
- 2-level FIFO architecture
 - L1 FIFO: de-randomize the injecting charge
 - L2 FIFO: match the in/out data rate
 - between core and interface
- Trigger-less & Trigger mode compatible
 - Trigger-less: 3.84 Gbps data interface
 - Trigger: data coincidence by time stamp
only matched event will be readout
- Features standalone operation
 - On-chip bias generation, LDO, slow control, etc



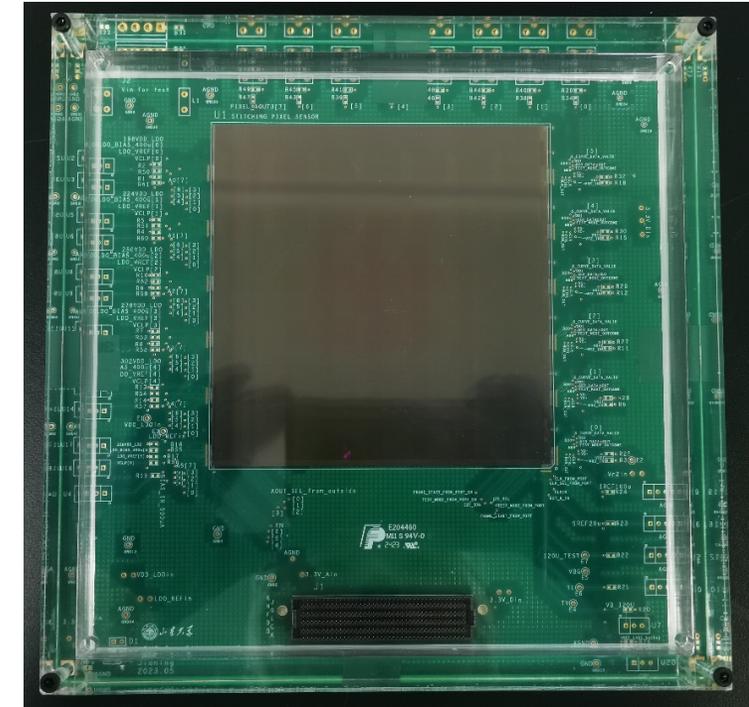
R&D efforts and results: R & D for curved MAPS

■ Stitching chip design (by ShanDong U.)

- 350nm CIS technology Xfabs
- Wafer level size after stitching $\sim 11 \times 11 \text{ cm}^2$
- reticle size $\sim 2 \times 2 \text{ cm}^2$
- 2D stitching
- Engineering run, chip under testing



Stitching chip : $11 \times 11 \text{ cm}^2$



Key technology

Stitching

Status

11*11cm stitched chip with Xfab 350nm CIS

CEPC Final goal

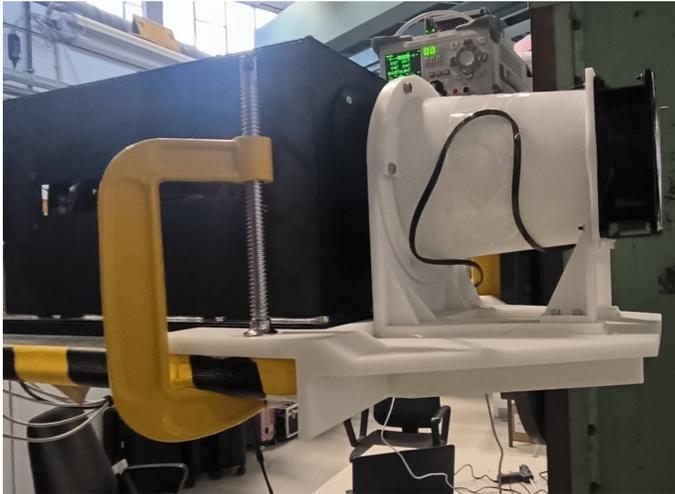
65nm CIS stitched sensor

R&D status and final goal

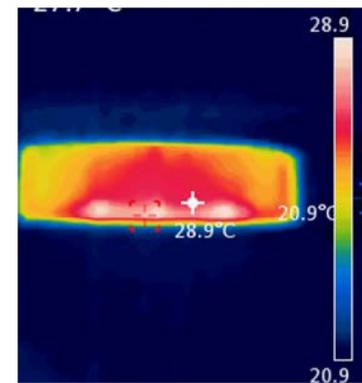
Key technology	Status	CEPC Final goal
CMOS chip technology	Full-size chip with TJ 180nm CIS	65nm CIS
Detector integration	Detector prototype with ladder design	Detector with bent silicon design
Spatial resolution	4.9 μm	3-5 μm
Detector cooling	Air cooling with 1% channels (24 chips) on	Air cooling with full power
Bent CMOS silicon	Bent Dummy wafer radius $\sim 12\text{mm}$	Bent final wafer with radius $\sim 11\text{mm}$
Stitching	11 \times 11cm stitched chip with Xfab 350nm CIS	65nm CIS stitched sensor

R&D efforts: Air cooling in vertex prototype

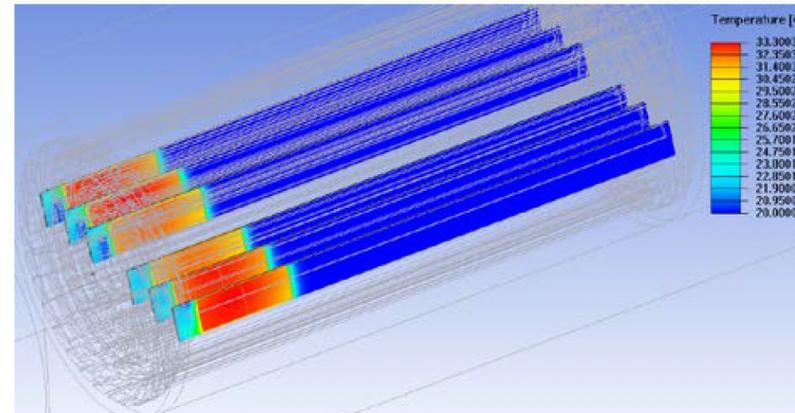
- Dedicated air cooling channel designed in prototype.
 - Measured Power Dissipation of Taichu chip: $\sim 60 \text{ mW/cm}^2$ (17.5 MHz in testbeam)
 - Before (after) turning on the cooling, chip temperature $41 \text{ }^\circ\text{C}$ ($25 \text{ }^\circ\text{C}$)
 - In good agreement to our cooling simulation
 - No visible vibration effect in spatial resolution when turning on the fan



Chip temperature under cooling during beam test: Max $28.9 \text{ }^\circ\text{C}$



Prototype cooling simulation: Max $33.3 \text{ }^\circ\text{C}$



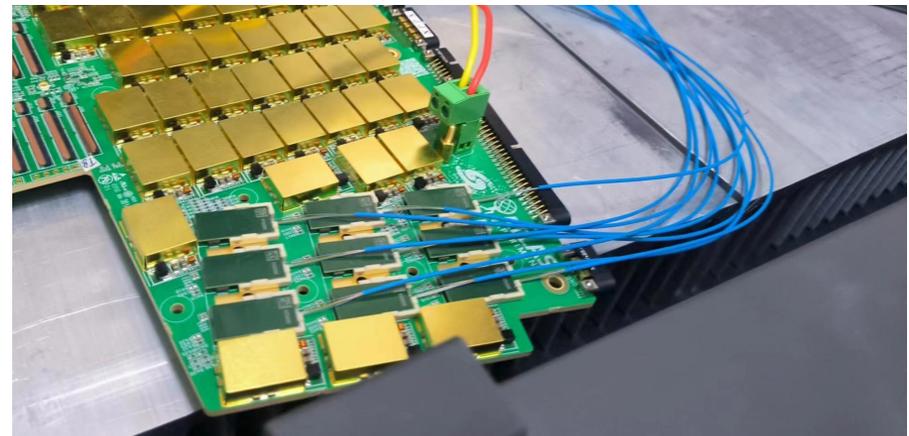
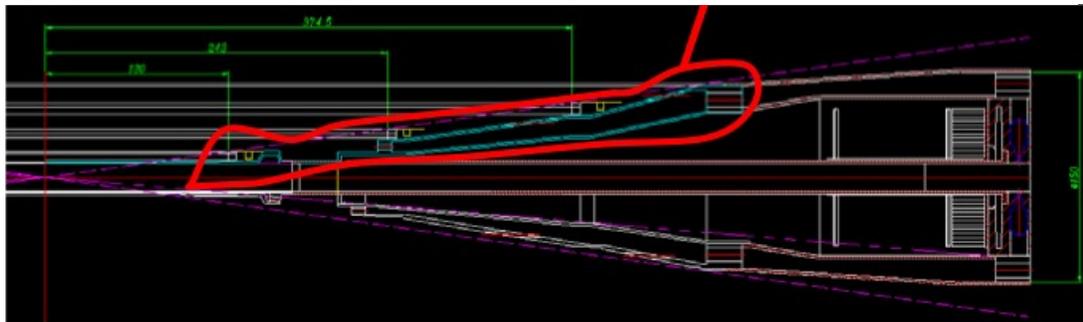
Key technology	Status	CEPC Final goal
Detector cooling	Air cooling with 1% channels (24 chips) on	Air cooling with full power

Vertex technologies: Cables and services

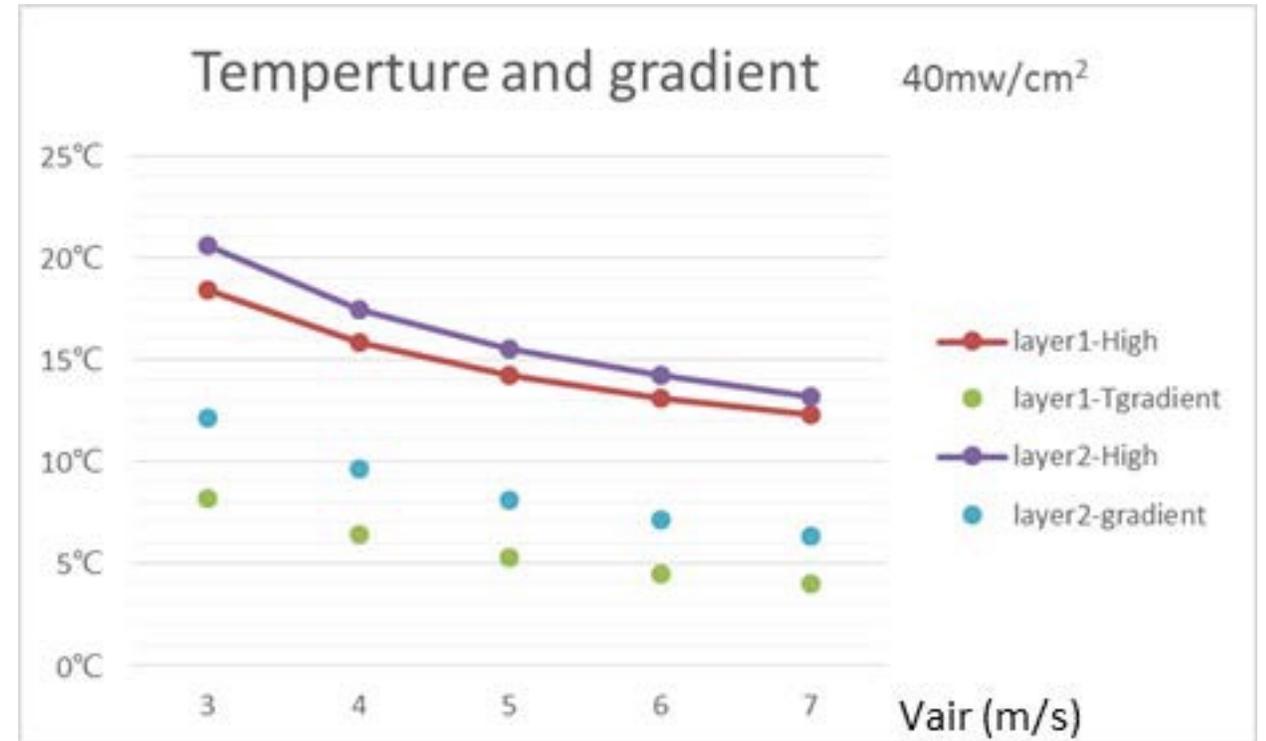
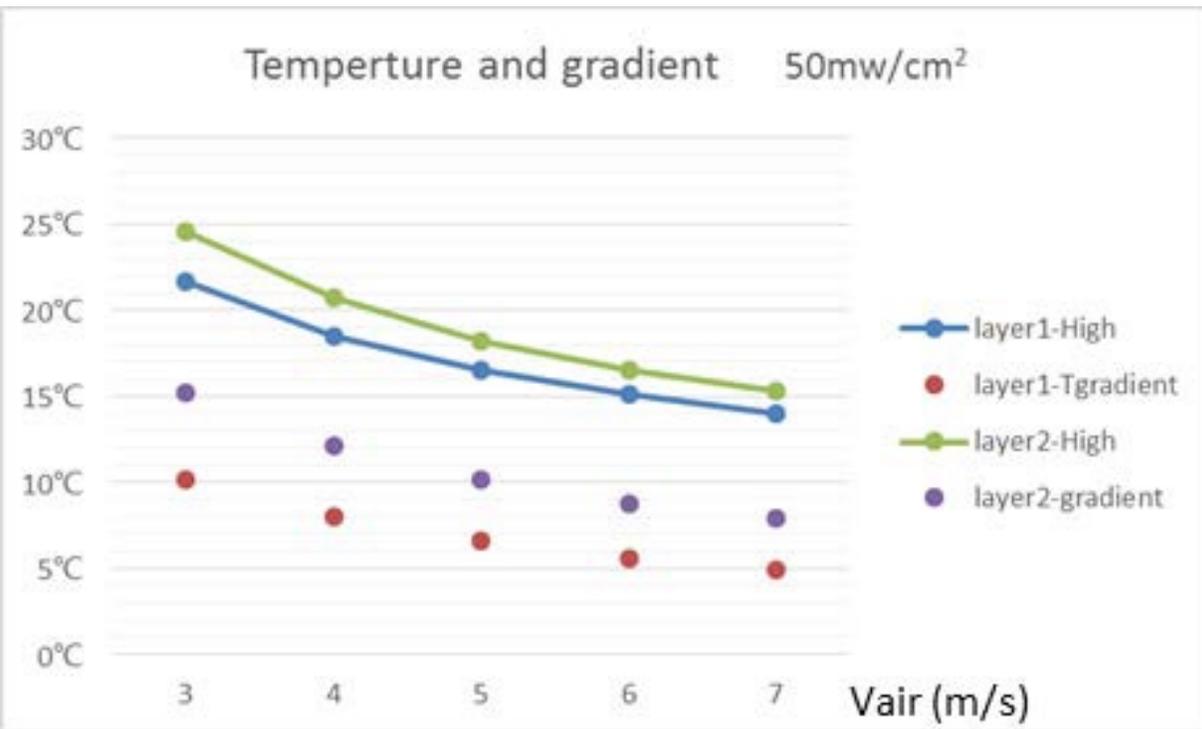
- Limited space in the MDI region for cables and services
 - Utilizes DC-DC powering; MAPS silicon substrate requires a common negative bias
 - Signal are transmitted through a flexible PCB and then converted to optical fiber.



Example from ATLAS HGTD upgrade

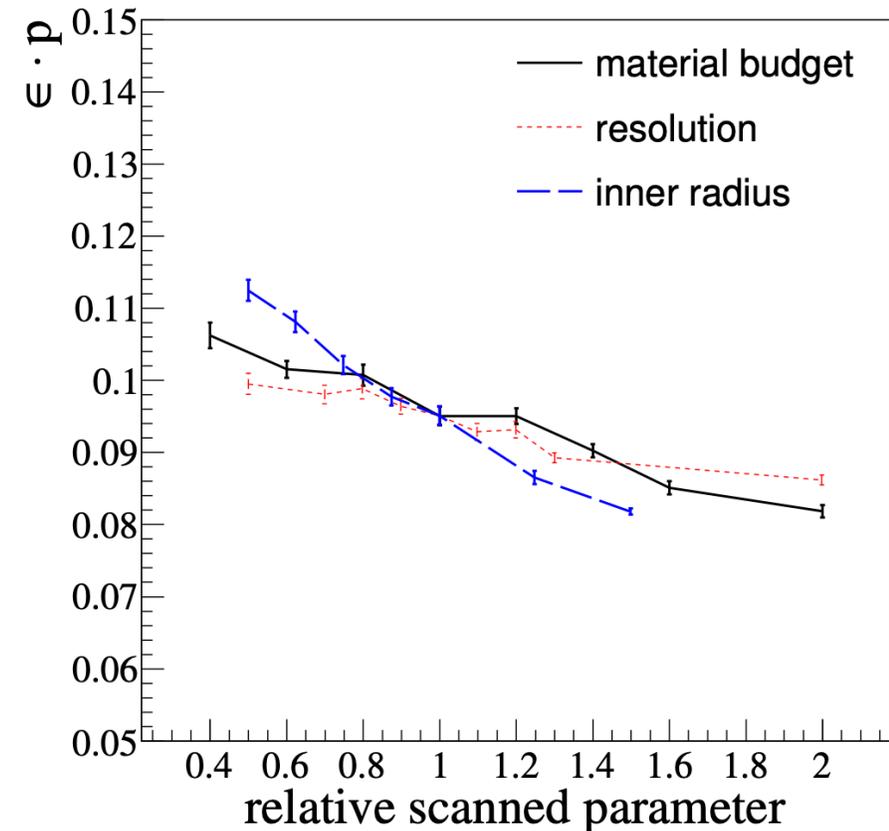
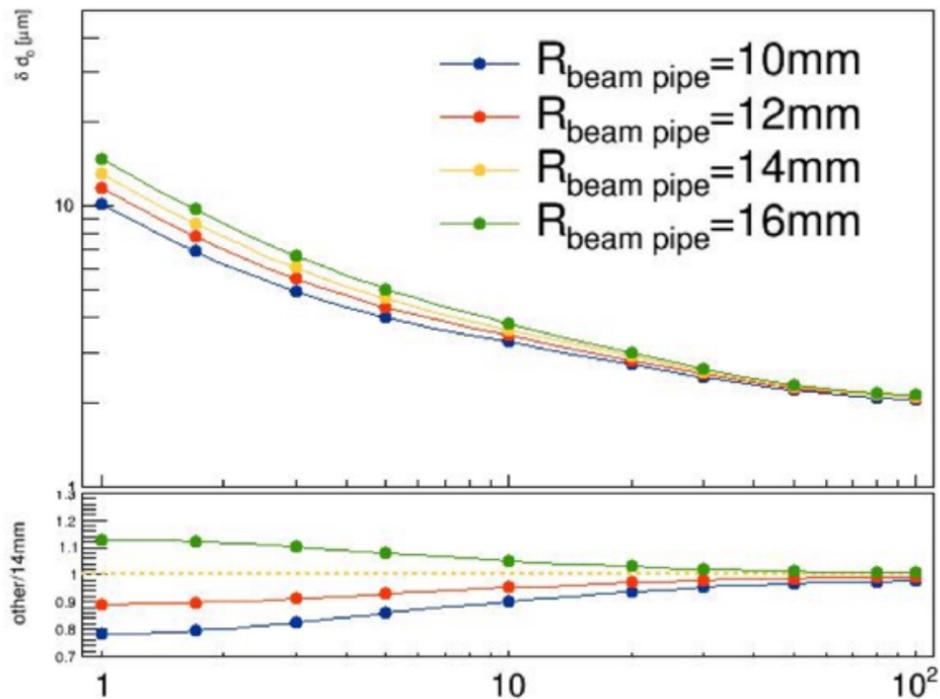


Backup : air cooling simulation



Vertex Requirement

- 1st priority: Small inner radius, close to beam pipe (11mm)
- 2nd priority: Low material budget <0.15% X0 per layer
- 3rd priority: High resolution pixel sensor: 3~5 μm

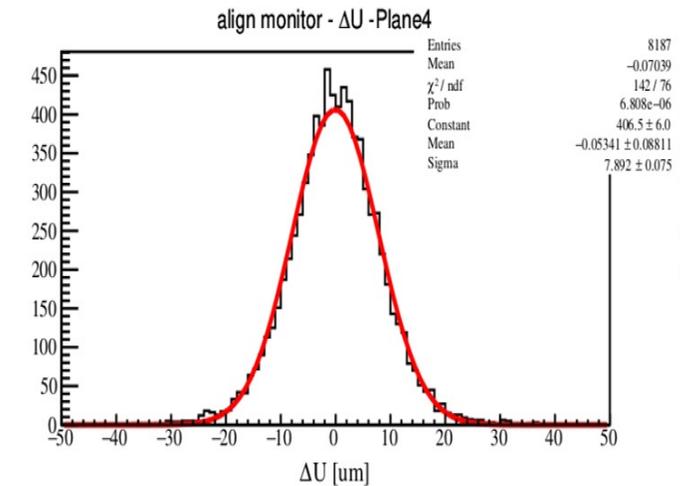
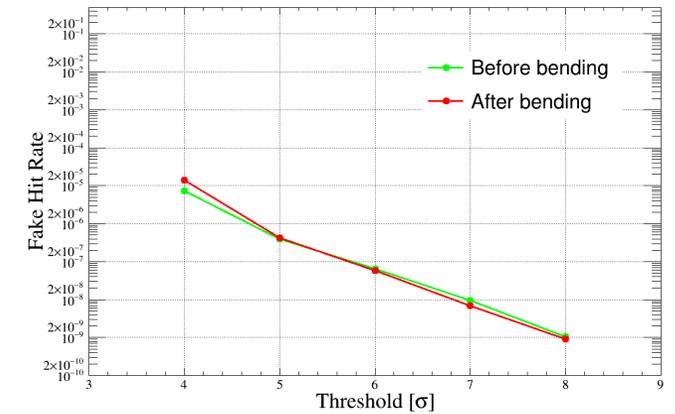
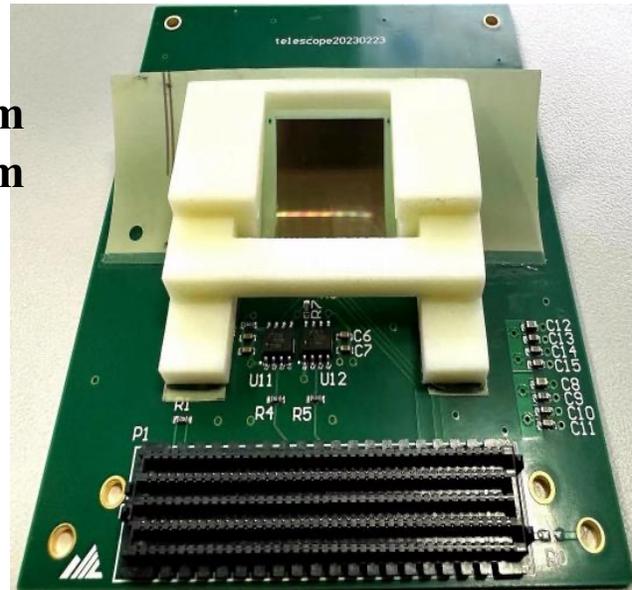
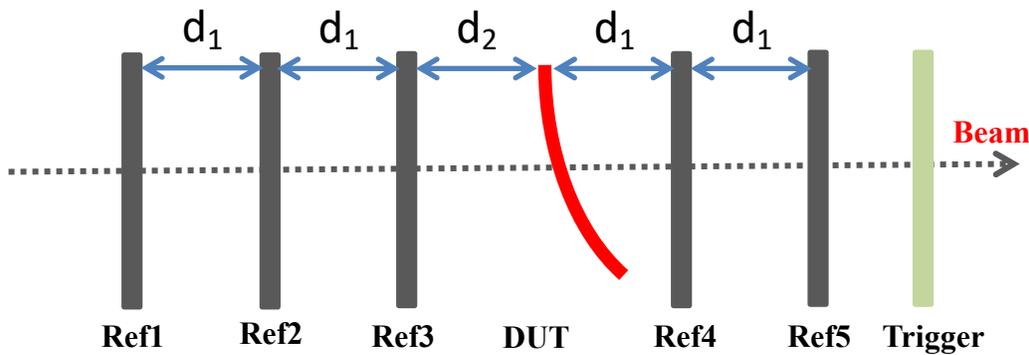


R&D efforts : Curved MAPS testbeam

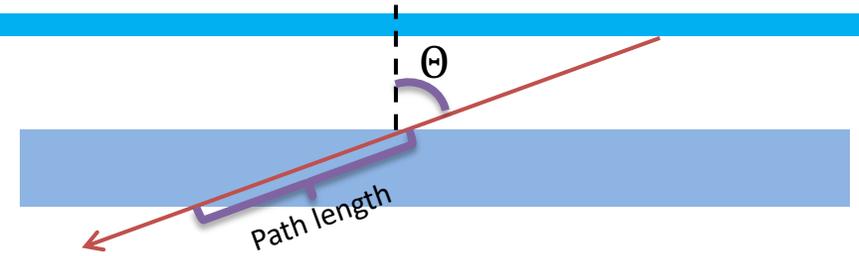
R & D of curved maps with MIMOSA28 chip

– No visible difference in noise level or spatial resolution before/after bending

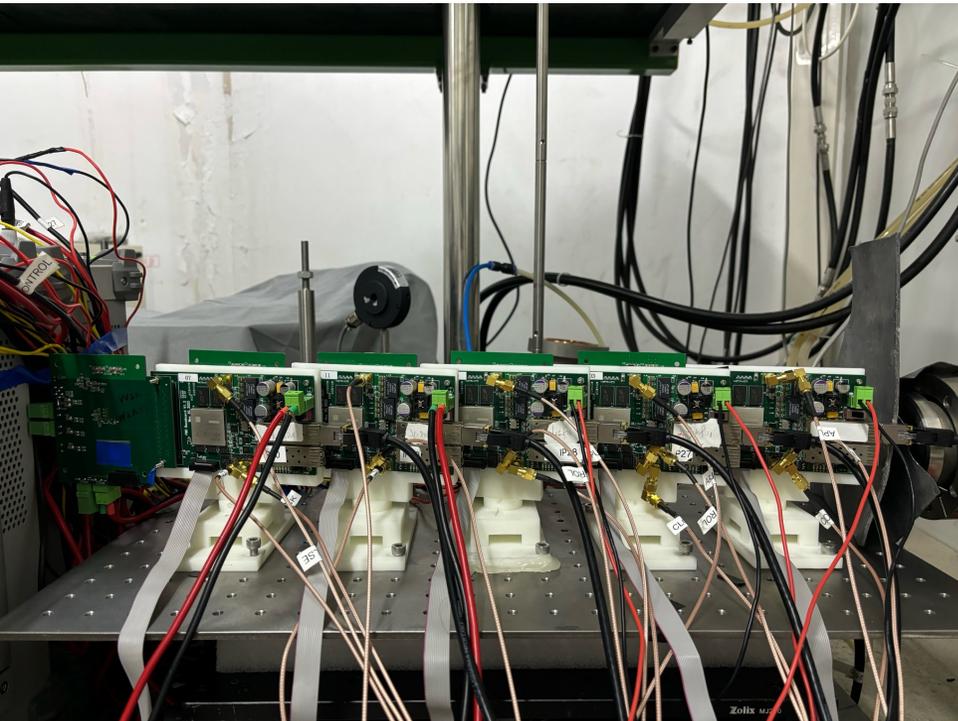
$d_1 = 25 \text{ mm}$
 $d_2 = 30 \text{ mm}$



Long barrel : cluster size vs incident angle

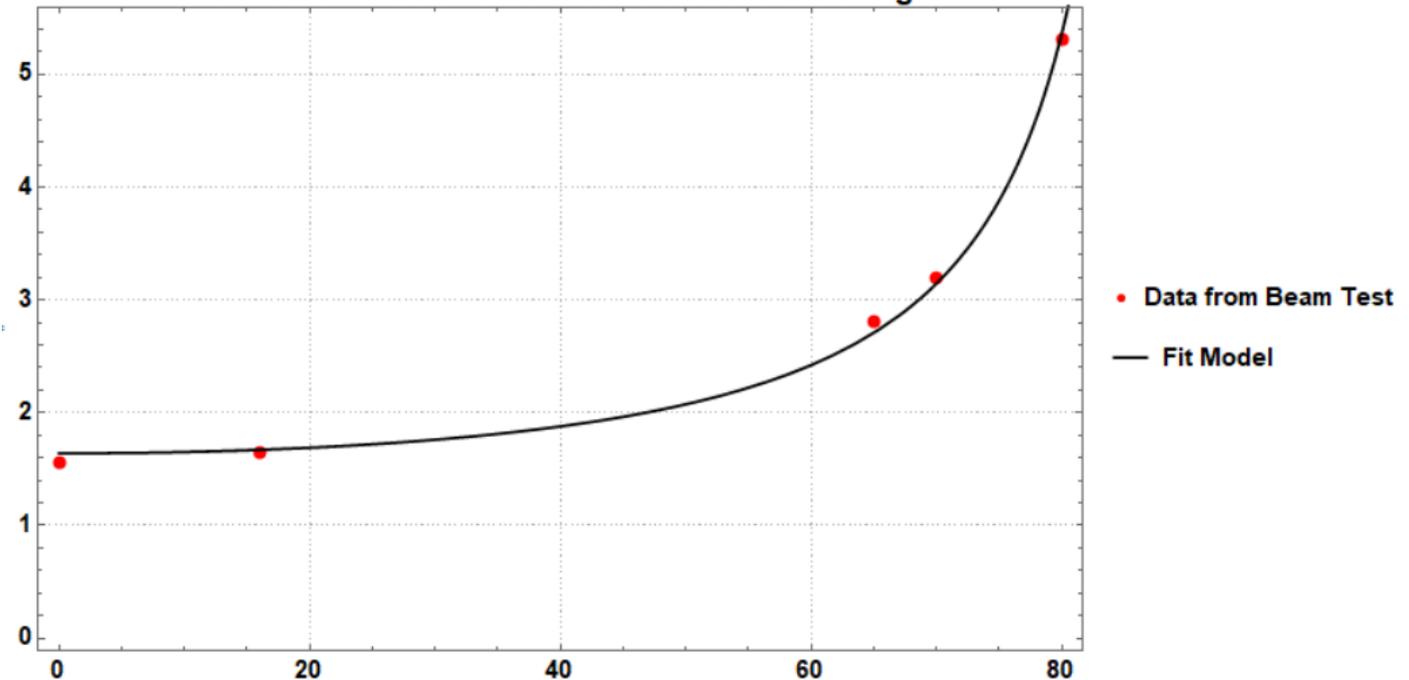


$$\text{Cluster size} = a \times \sec\theta + b$$



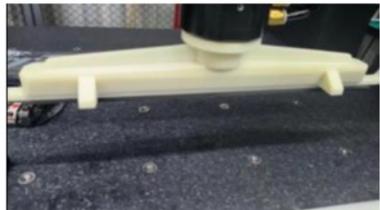
Cluster size

Correlation: Cluster Size - Corrected Incident Angle



TaichuPix3 vertex detector prototype

New pickup tools



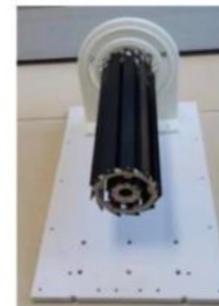
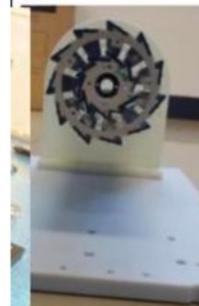
Dummy ladder glue automatic dispensing using gantry



Ladder on wire bonding machine



Dummy Ladder on holder



The first vertex detector (prototype) ever built in China

Ladder support tools



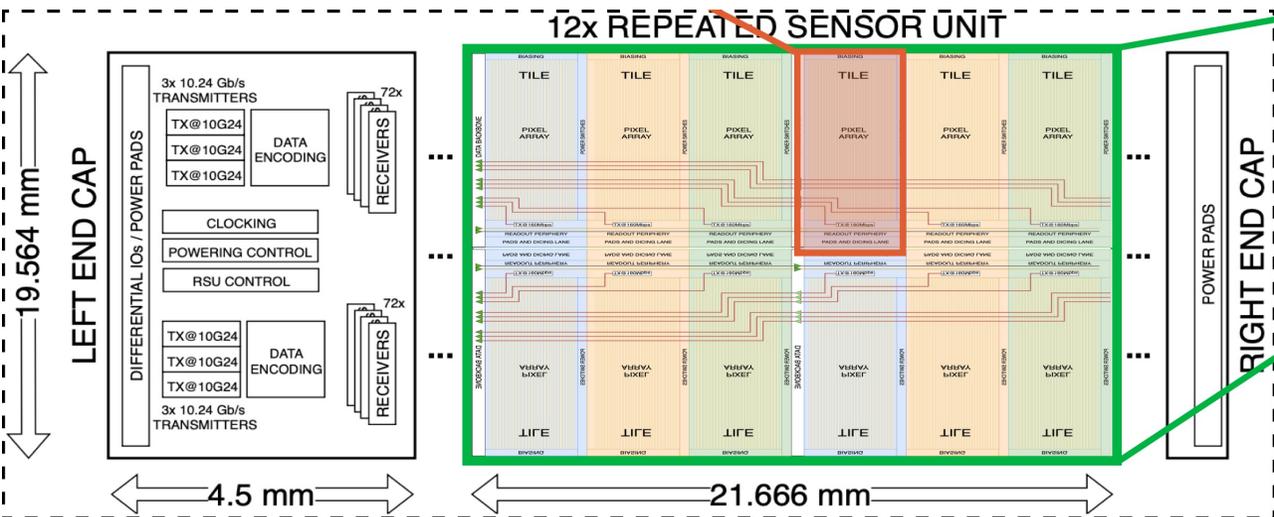
Ladder loaded on vertex detector



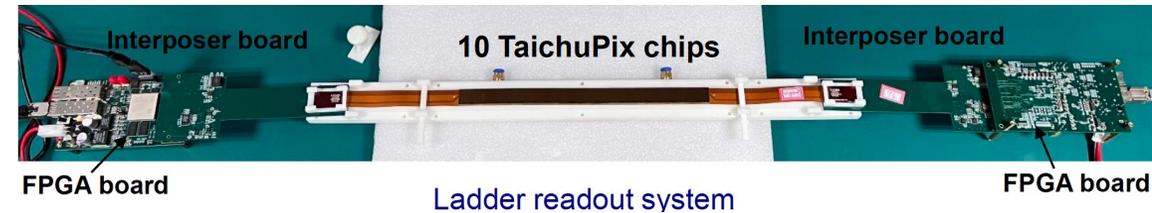
Ladder Electronics

- Baseline: stitching and RDL metal layer on wafer to replace PCB
- Alternative: flexible PCB
 - Signal, clock, control, power, ground will be handled by control board through flexible PCB

Baseline: ALICE ITS3 like stitching



Alternative: flexible PCB



叠层	厚度	材料	颜色	其他
Layer 1	12.5 um	Coverlay	(yellow)	
	20 um	Coverlay Adhesive		
	24 um	ED Base Copper	12 um + Plated 18 um	
	13 um	Polyimide (Adhesiveless)		
Layer 2	12.5 um	Adhesive		
	12 um	ED Base Copper	12 um	
	25 um	Polyimide (Adhesiveless)		Flex Thickness 挠折区
Layer 3	12.5 um	Adhesive		
	13 um	Polyimide (Adhesiveless)		
	24 um	ED Base Copper	12 um	
Layer 4	13 um	Adhesive		
	24 um	ED Base Copper	12 um	
	20 um	Coverlay Adhesive		
	12.5 um	Coverlay	(yellow)	
FPC厚度	213 um	Spec: 210 um +/- 50 um		
Created By:	HLJ			
Date:				

[1] ALICE ITS3 TDR: <https://cds.cern.ch/record/2890181>